Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination YOUNG ET AL. | Examiner | Art Unit | Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,897,020	05-2005	Link et al.	435/6
	В	US-			
	O	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Ι	US-			
	_	US-			
	7	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					·
	Q					
	R	,				
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	C	Jarvik et al., Biotechniques, 1996, 20: 896-904.				
	>	Smith, Biotechniques, 1997, 23: 116-120.				
	w	Velculescu et al., Science, 1995, 270: 484-487.				
	x	1996 New England Biolabs, Inc. Catalog, p. 39.				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | YOUNG ET AL. | Examiner | Art Unit | Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	ÚS-			
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Η	US-			
	1	US-			
	J	US-			•
	К	US-			
	L.	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	ο.					
	Р					
	Q					
	R					·
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Morin et al., Proc Natl Acad Sci USA, 2001, 98: 15050-15055.
	>	Townley et al., Genome Research, 1997, 7: 293-298.
	w	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.